



# SPECIFICATION

PN: SJK-6MH14745M3C0430A6

深圳市晶科鑫实业有限公司

SHENZHEN CRYSTAL TECHNOLOGY INDUSTRIAL CO., LTD.

VER	DESIGNED	CHECKED	APPROVED
A1	何丹斌	李相同	刘忠亮

## CUSTOMER APPROVAL

SPECIFICATION :		晶振 / Half Size / 14.7456MHz	
SJK PN. :		SJK-6MH14745M3C0430A6	
CUSTOMER PN. :			
CHECKED 1	CHECKED 2	APPROVED	DATE
Result: <input type="checkbox"/> PASS <input type="checkbox"/> FAIL <input type="checkbox"/> OTHER			

## FEATURE

- Small Size as small as 12.8× 12.8× 5.0mm.
- Hybrid IC Circuit Construction.
- CMOS compatible output.
- 5V and 3.3V supply model available.
- All metal, hermetically sealed welded package.
- High precision characteristic covering to high frequency range.
- RoHS and Pb Free compliant.

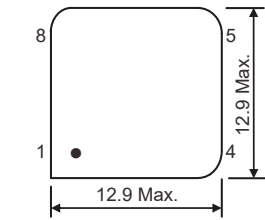
## ELECTRICAL SPECIFICATIONS

Model Type		Half Size
Fan Out Type		CMOS
Supply Range		3.3V ±10%DC
Frequency Range		14.7456MHz
Operating Temperature		-40~85°C
Frequency Range Input Current		15mA Max
Rise time(Tr) and Fall time(Tf)		5ns Max
Frequency Stability	All Conditions	±30ppm
Symmetry	AT 1/2 Vdd	45/55%
Output level	"0"level(Vol)	10%VccMax
	"1"level(Voh)	90%VccMin
Output load	CMOS	15PF
Storage temperature		-55~125°C

# Crystal Oscillator CMOS Output Half Size 6MH Series

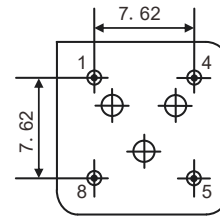
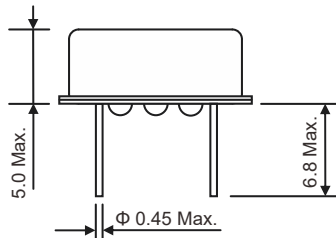


## DIMENSION (Unit: mm)



### Pin Connections

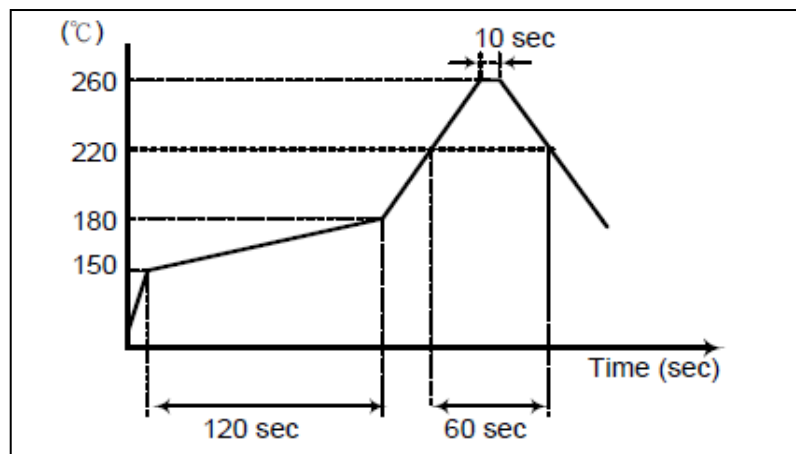
Pin No.	Connection
1	NC (Not connect)
4	GND
5	Output
8	Vdd



## MARK

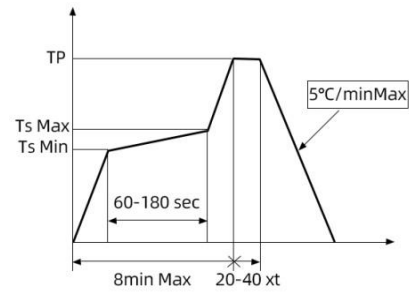


## REFLOW CONDITION



The reflow temperature profile may vary depending on the product model, specifications and frequency range. Refer to the individual product specifications for details

**RELIABILITY TEST SPECIFICATIONS**

Test item	Equipment	Condition	Specification
1.SOLDERABILITY TEST	SJK-REL001、RC-328A	TP:260℃ TsMax: 200℃ TsMin: 150℃ 2 time 	MIL-STD-883E Method 2003.7
2. HERMETICITY TEST	HELIOT-306S	Pressurized 0.4~0.5Mpa ethanol sealed tank for 10 minutes	MIL-STD-883E Method 1014.10
3. VIBRATION TEST	HG-V4、S&A 250B	Enable Crystal(10g) from 10-55-10Hz,X、Y、Z horizontal,1 Minute vibration/time, 1time/ 2 hours.	MIL-STD-883E Method 2007.3
4. MECHANICAL SHOCK	HPC-200、S&A 250B	Enable Crystal 50G(490m/s <sup>2</sup> ) time=11 ms speed=3.4 m/s half sine wave oscillation	JIS C6701
5. DROP TEST	HARD BOARD.S&A250B	75cm High,3 times on hard board	MIL-STD-202F Method 213B
6. HIGH&LOW TEMP STORAGE TEST(Static test)	H-PTH-80CK & HM101-3ABN, S&A 350B/250B	High temperature: 125℃±2℃,1000hr; Low temperature:-40℃±3℃,1000hrs	MIL-STD883C, METHOD 1011.8
7. TEMP & HUM CYCLING TEST	H-PTH-80CK CHAMBE, S&A 350B/250B	Temperature:-10℃±2℃~65℃±2℃,Humidity:93±3%,1 cycle need 24 hrs. 5cycles.	MIL-STD-883E Method 1005.8
8. HIGH TEM. & HUM.STORAGE TEST	H-PTH-80CK CHAMBE, S&A350B/250B	Temperature:85℃±2, Humidity:85+3,-2%,Store 96 hrs	JIS C6701
9. AGING TEST	H-PTH-80CK CHAMBE, S&A350B/250	Temperature:85℃±2, Store 1000 hrs	JIS C5023

### REVISION RECORD ( SJK-6MH14745M3C0430A6)

Rev	Revise contents	Reason	Reviser	Checked	Approved
A1	Initial released	--	贺丹斌	李相同	刘惠光